

## IGBT

## TRENCHSTOP<sup>™</sup> IGBT3 Chip SIGC41T120R3LE

### Data Sheet

## Industrial Power Control

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### TRENCHSTOP<sup>™</sup> IGBT3 Chip

#### Features:

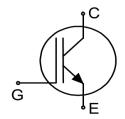
- 1200V trench & field stop technology
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

#### **Recommended for:**

• Power modules

#### Applications:

Drives



Chip Type	V <sub>CE</sub>	<b>I</b> Cn <sup>1</sup>	Die Size	Package
SIGC41T120R3LE	1200V	40A	6.5mm x 6.37mm	Sawn on foil

#### **Mechanical Parameters**

Die size		6.5 x 6.37		
Emitter pad size		See chip drawing	mm <sup>2</sup>	
Gate pad size		1.139 x 1.139		
Area total		41.405		
Thickness		120	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	640		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is stru- recommended not to consume the Ni layer complet production process		
Die bond		Electrically conductive epoxy glue and soft so	lder	
Wire bond		Al, ≤500µm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2 <6 months	25°C,	
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or humidity <25%RH, temperature 17°C – 25°C, <6		

<sup>&</sup>lt;sup>1</sup> Nominal collector current at  $T_{C}$ =100°C for chip packaged in TO packages, see application example cited on page 5.



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T <sub>vj</sub> =25°C	V <sub>CE</sub>	1200	V
DC collector current, limited by $T_{\rm vj max}^2$	I <sub>C</sub>	-	A
Pulsed collector current, $t_p$ limited by $T_{vj max}^3$	I <sub>C,puls</sub>	105	A
Gate-emitter voltage	V <sub>GE</sub>	±20	V
Junction temperature range	T <sub>vj</sub>	-55 +175	°C
Operating junction temperature	T <sub>vj</sub>	-55 +150	°C
Short circuit data $^{3/4}$ V <sub>GE</sub> =15V, V <sub>CC</sub> =900V, $T_{vj}$ =125°C	t <sub>sc</sub>	10	μs
Reverse bias safe operating area <sup>3</sup> (RBSOA)	I <sub>C,max</sub> =80A	, V <sub>CE,max</sub> =1200V, <i>T</i> <sub>vj</sub> ≤12	5°C

#### Static Characteristics (tested on wafer), Tvj=25°C

Parameter	Symbol	Conditions	Value			Unit	
	Symbol Conditions		min.	typ.	max.		
Collector-emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> =0V, <i>I</i> <sub>C</sub> =1.5mA	1200	-	-		
Collector-emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =40A	1.4	1.7	2.1	V	
Gate-emitter threshold voltage	V <sub>GE(th)</sub>	$I_{\rm C}$ =1.5mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5		
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1200V, V <sub>GE</sub> =0V	-	-	4.8	μA	
Gate-emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V, V <sub>GE</sub> =20V	-	-	600	nA	
Integrated gate resistor	r <sub>G</sub>			6		Ω	

#### **Electrical Characteristics**<sup>3</sup>

Parameter	Symbol	Conditions	Value			Unit
Falalletei	Symbol	Conditions	min.	typ.	max.	Unit
Collector-emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =40A, <i>T</i> <sub>vj</sub> =150°C	-	2.3	-	V
Input capacitance	C <sub>ies</sub>	$V_{CE}=25V$ ,	-	2500	-	~F
Reverse transfer capacitance	C <sub>res</sub>	V <sub>GE</sub> =0V, <i>f</i> =1MHz <i>T</i> <sub>vj</sub> =25°C	-	110	-	pF

<sup>&</sup>lt;sup>2</sup> Depending on thermal properties of assembly.

<sup>&</sup>lt;sup>3</sup> Not subject to production test - verified by design/characterization.

<sup>&</sup>lt;sup>4</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



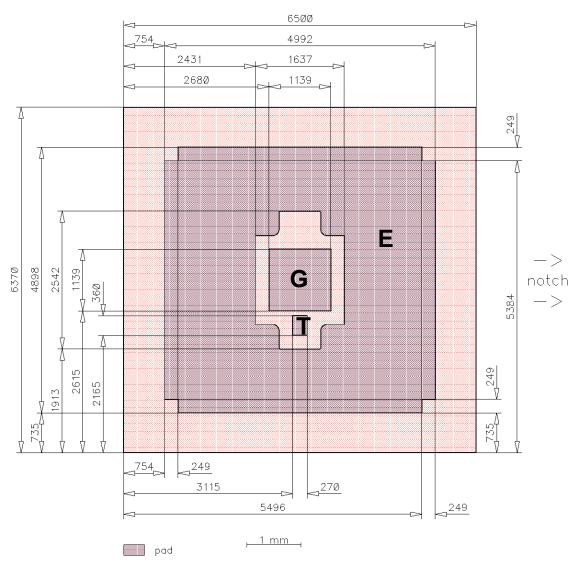
#### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

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#### **Chip Drawing**



Die-Size 6500 um × 6370 um

- $\mathbf{E} = \text{Emitter}$
- $\mathbf{G} = \text{Gate}$
- T = Test pad do not contact

L7651N, L7651U, L7651F



#### **Bare Die Product Specifics**

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

#### Description

AQL 0.65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Revision	Subjects (major changes since last revision)	Date
2.0	Release of final datasheet, change wafer size to 200mm	30.04.2010
2.1	Additional basic types L7651N, L7651U, L7651F	27.06.2014
2.2	Minor changes, chip drawing	06.02.2015
2.3	Update disclaimer	19.08.2015

#### **Relevant Application Notes**





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